



Sampling Oscilloscope Training

June 30th / July 1st 2010
- Olympiaturm -

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Application Engineer

Brief introduction to Pico Technology



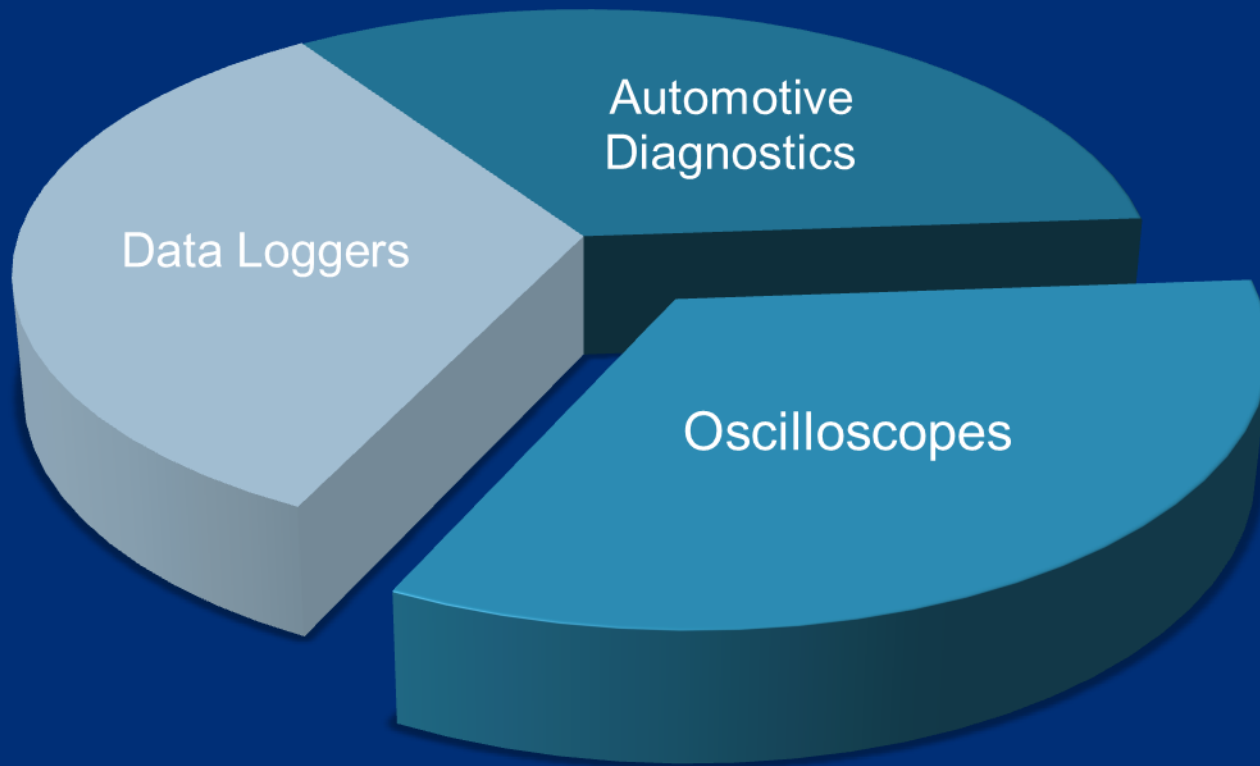
- Company Name Pico Technology Limited
- Founded 1991
- Headquarters Cambridge, UK
- Distributor in Germany Meilhaus Electronic GmbH

PUT CONTACT INFO – Chris Stacey

- Here today at Olympiaturm



Pico Technology Product Areas



Introduction to sampling scopes

Real-time scope Vs Sampling scope



Real-time Oscilloscopes

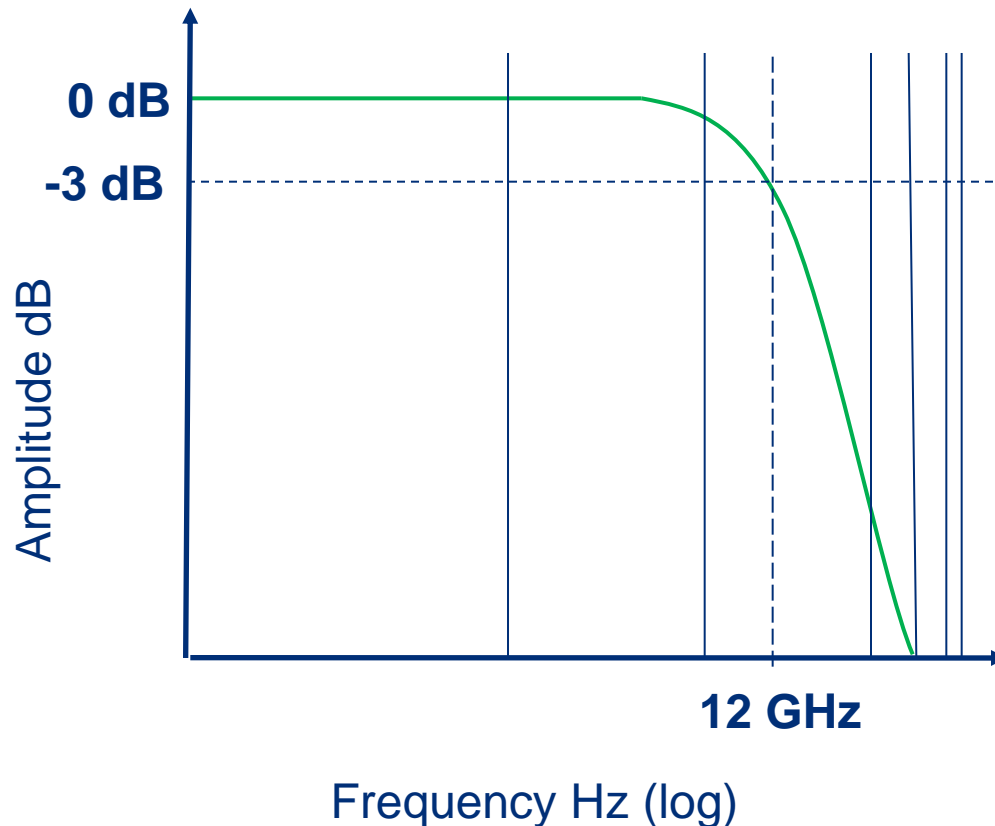
- Can capture single instantaneous or repetitive events
- Lower ADC resolution, but high sample rate increases error
- Long record length
- Advanced triggers to capture intermittent events
- Serial bus decoding
- Ideal for general use and fault diagnosis
- Real-time GS/s sampling is **EXPENSIVE**

Sampling Oscilloscopes

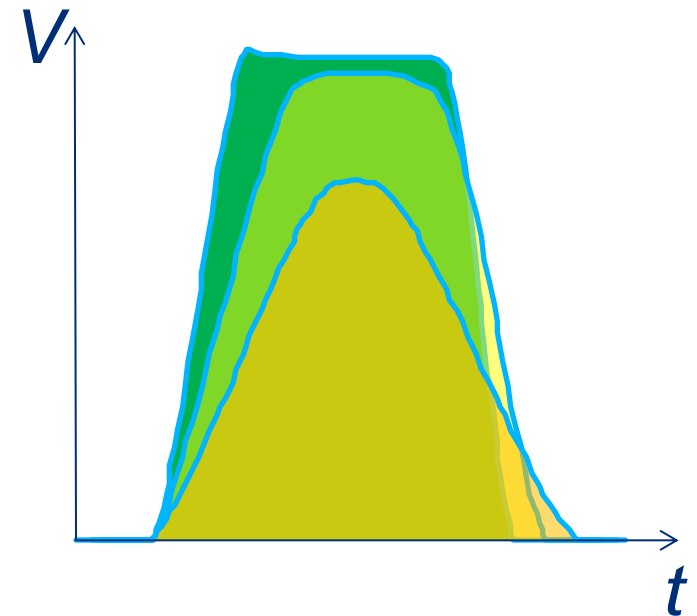
- Can only capture repetitive waveforms
- Have lower sample rate to increase ADC resolution
- Lower noise floor
- Wider bandwidth for lower budget
- Lower intrinsic jitter
- Eye diagrams and mask testing
- Best choice for TDR/TDT measurement
- Lower cost of ownership

Analog bandwidth

“Analog bandwidth” is the maximum frequency that can pass through the front end of an oscilloscope



- Choose a scope with enough bandwidth for the application:
 - Signal transition time
 - Signal slew rate and rise time
- Effects of too little bandwidth:
 - Amplitude and timing errors
 - Loss of high frequency aberrations
 - Errors in automatic measurements

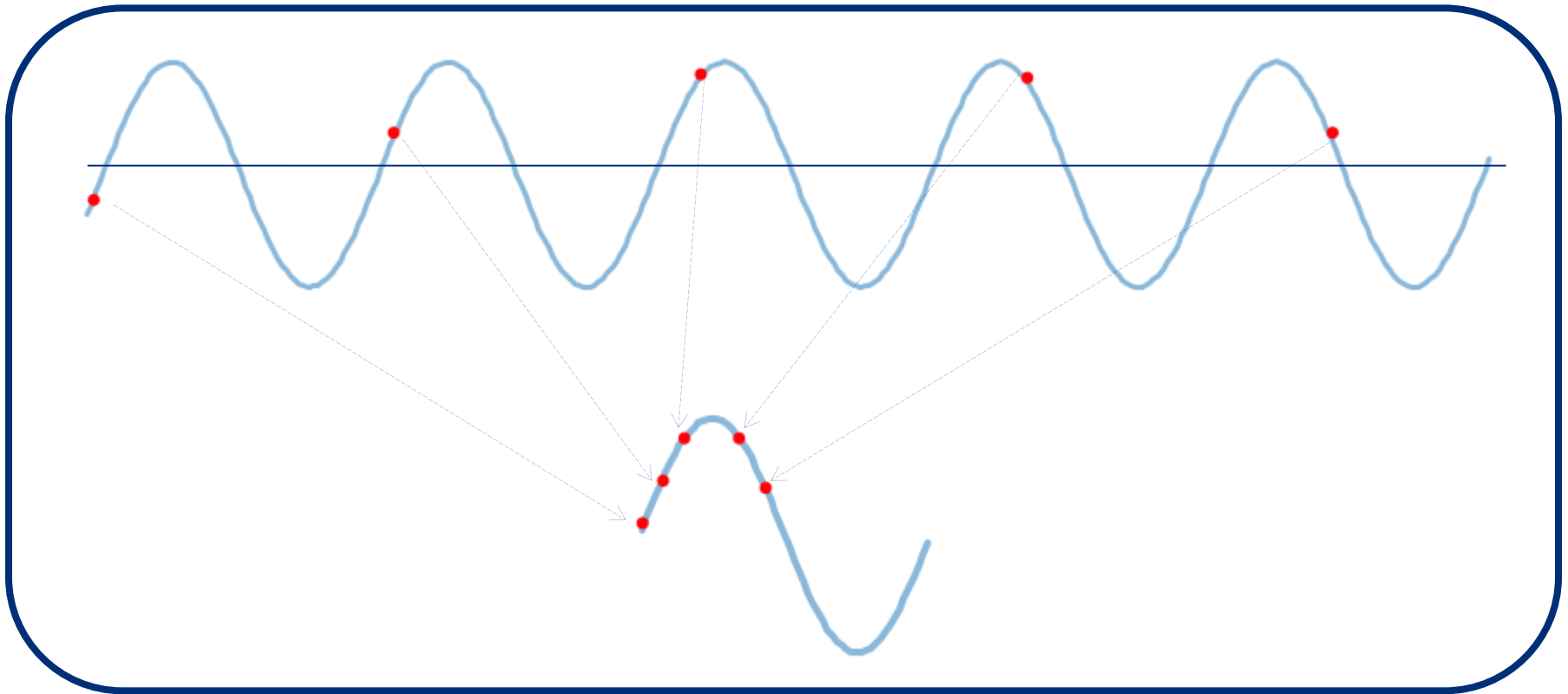


Rule of thumb...

$$BW = \frac{0.35}{t_{\text{rise}}}$$

$$t_{\text{rise}} = \frac{0.35}{BW}$$

Sequential Sampling – as used with PicoScope 9000



- Data points are acquired sequentially from many cycles to build one screen image
- PicoScope 9000 sample rate is 200 kS/s, bandwidth is 12 GHz

PicoScope 9000 Applications



SIGNAL ANALYSIS

- Electrical standards compliance testing
- Eye-diagram analysis
- Spectrum analysis
- Statistical analysis

TIMING ANALYSIS

- Automatic parametric measurements
- Pulsed RF switches
- Compliance testing

R & D

- Microwave & RF characterisation
- High-energy physics
- Digital design
- PCB and connector transmission line testing

HIGH-SPEED DIGITAL COMMUNICATIONS

- Design and verification of telecom and datacoms elements
- Manufacturing and testing for ITU / ANSI conformance
- Crosstalk analysis
- TDR/TDT

SEMICONDUCTOR TESTING

- Microwave & RF characterisation
- High-energy physics
- Digital design
- Informative waveform displays

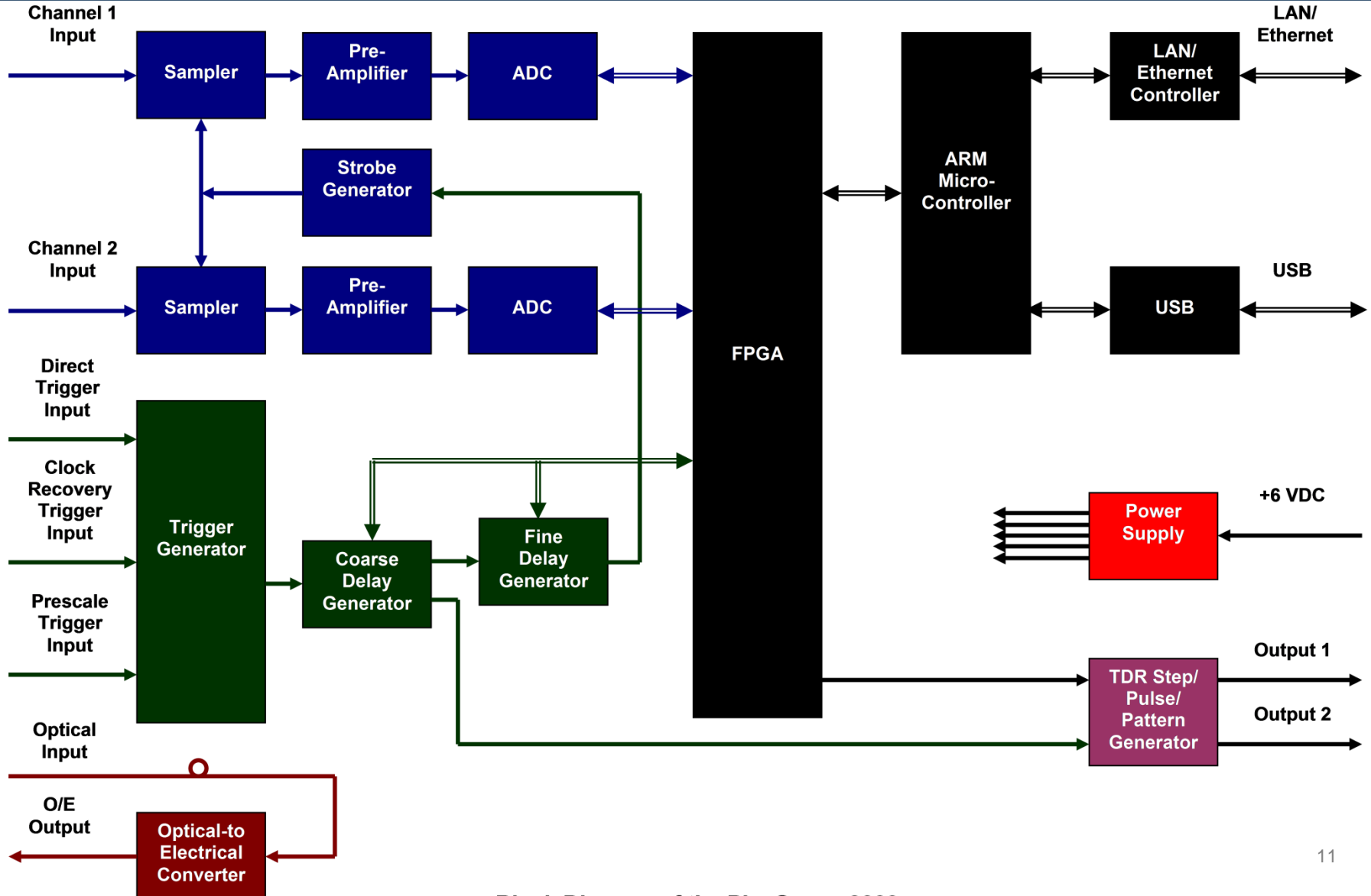
MANUFACTURING

- Limit and mask testing
- Testing for ITU / ANSI conformance
- Automatic test systems
- Auto-calibration routine



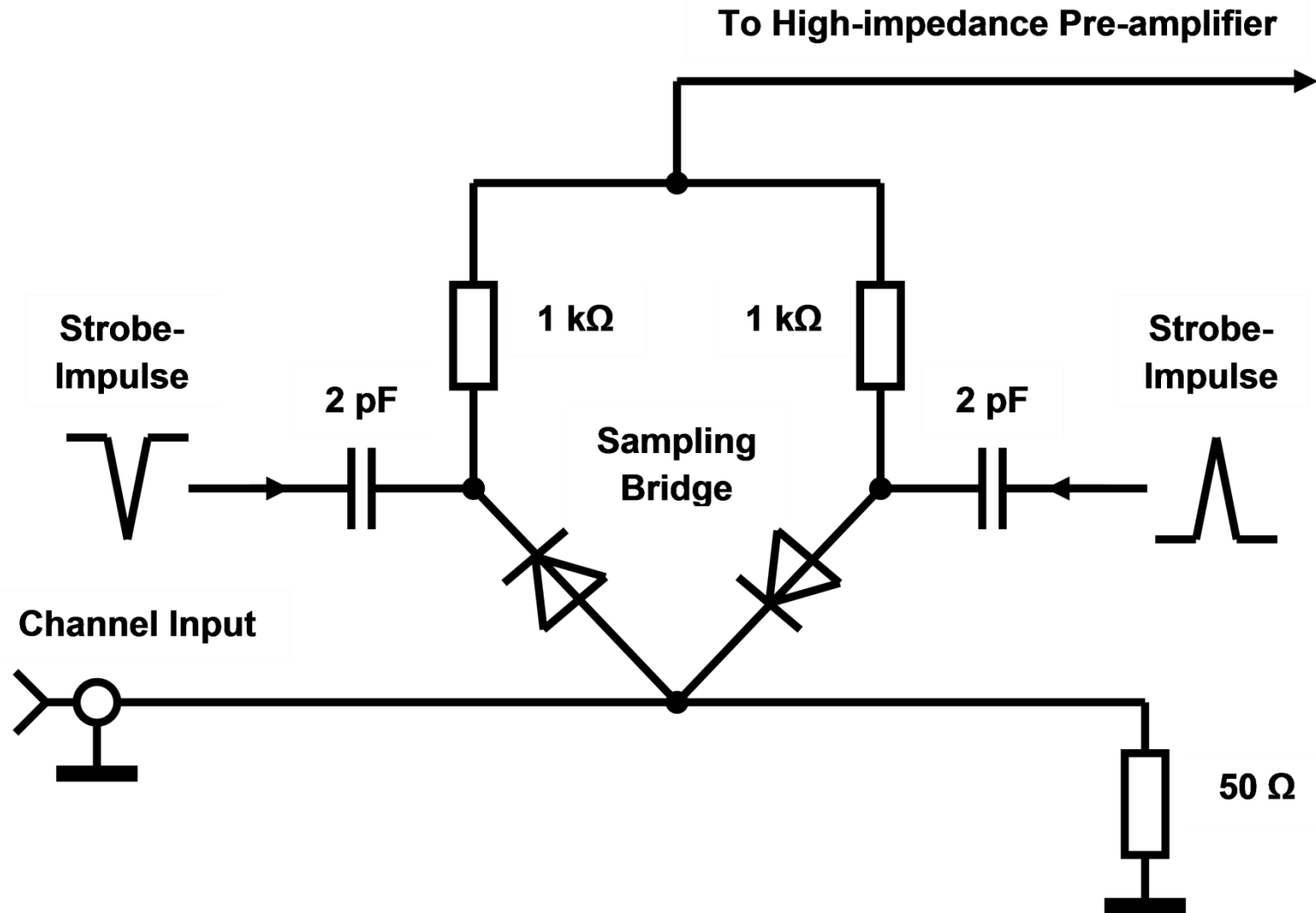
PicoScope 9000

PicoScope 9000 Block diagram

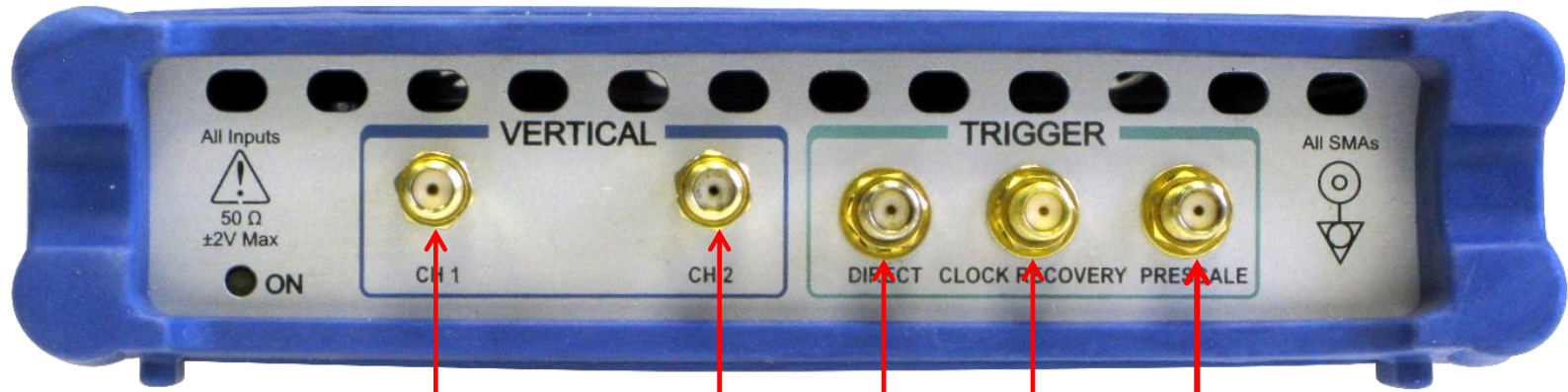


Block Diagram of the PicoScope 9000.

Sampling Diodes



PicoScope 9211A front panel



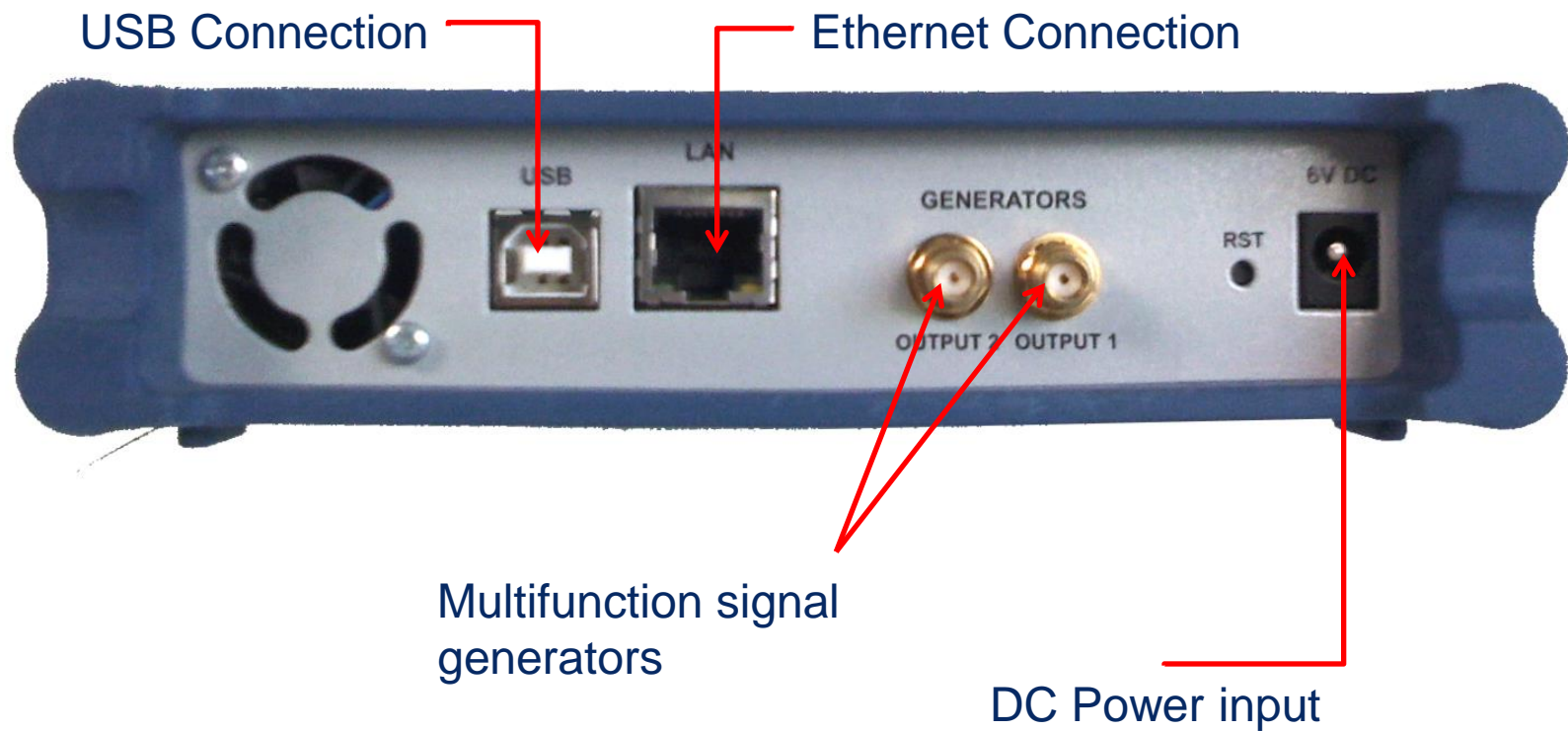
Electrical inputs

Direct trigger

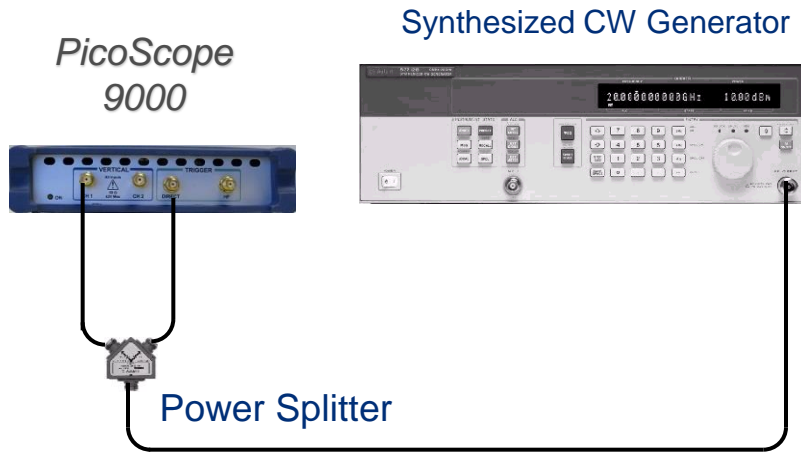
Clock recovery trigger

Prescaled trigger

PicoScope 9211A rear panel



Direct Trigger

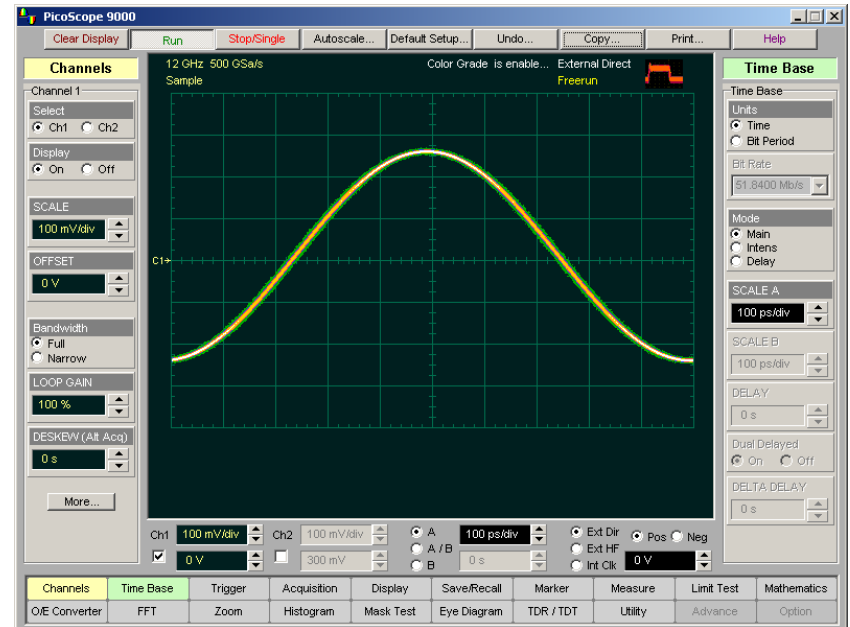


Equipment connections for Direct Trigger Test

Key specifications of Direct Trigger:

- ▶ DC to 1 GHz trigger bandwidth
- ▶ 100 mV p-p DC to 100 MHz, 400 mV p-p at 1 GHz sensitivity
- ▶ <3.5 ps max RMS jitter

The power of wide-bandwidth sampling oscilloscopes is largely useless without fast, low-jitter triggering.



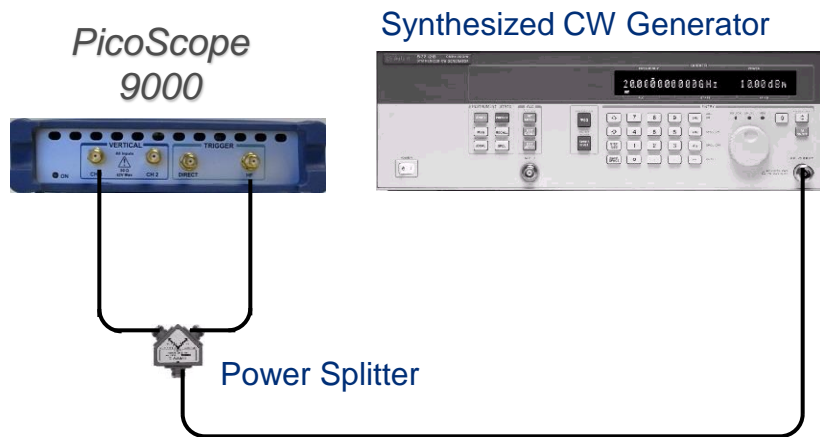
Typical picture of a 1 GHz signal using Direct Trigger

HF Prescaled Trigger

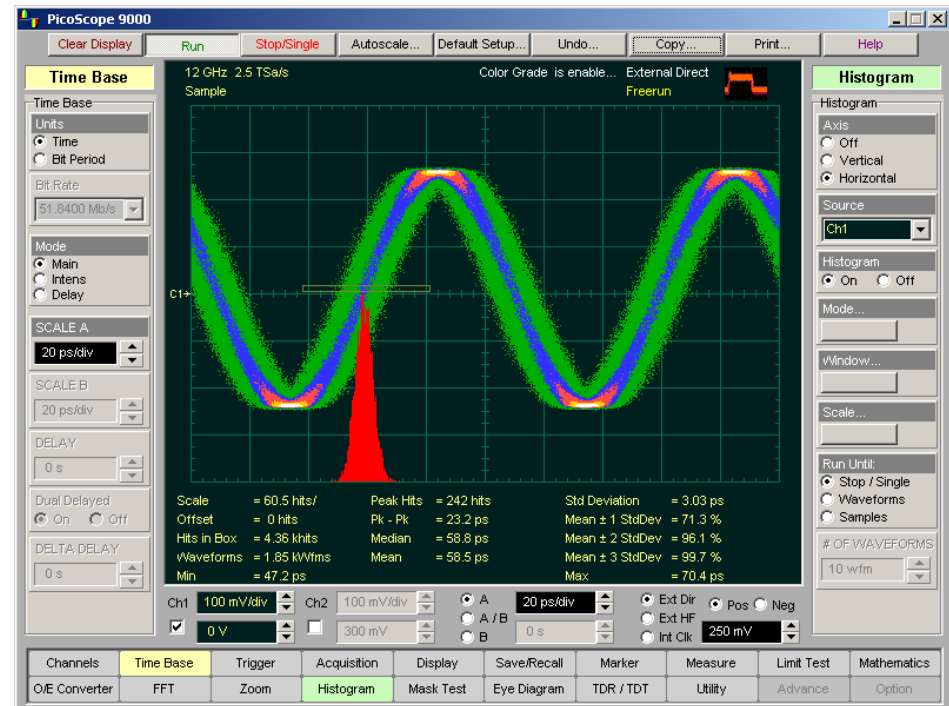


The PicoScope 9000 HF (prescaled) trigger is an AC-coupled 10-GHz prescaler for triggering on high-speed data without cumbersome manual adjustment.

The heart of the trigger is a low-noise GaAs frequency divider. Low RMS jitter <math>< 3.5\text{ ps}</math> typ. is possible.



Equipment connections for prescaled trigger test

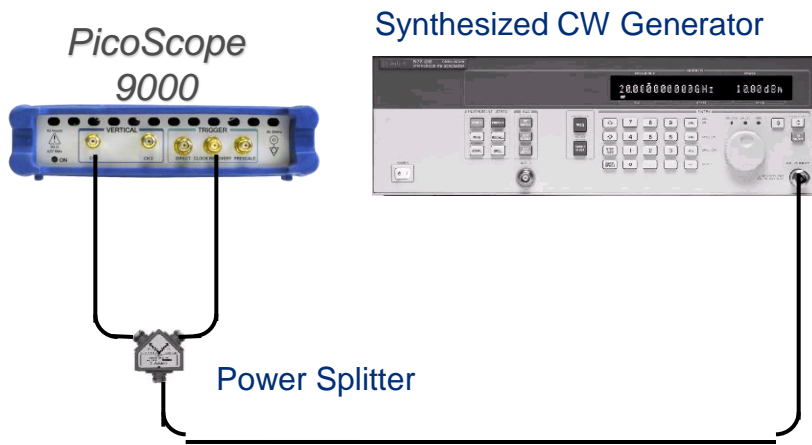


A 10 GHz sine-wave signal with prescaled trigger

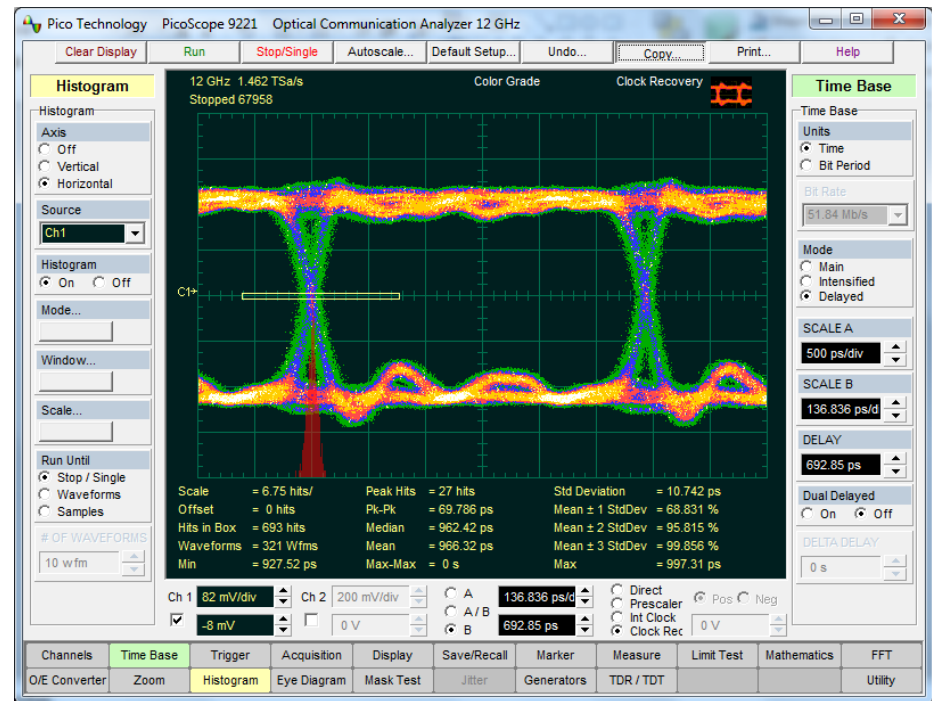
Clock recovery trigger

Use when the trigger source is an NRZ signal (without a dedicated trigger input) input with a data rate between 12.3 Mb/s and 2.3 Gb/s

Recovered Clock RMS Trigger Jitter, maximum: $1 \text{ ps} + 1.0\% \text{ of Unit Interval}$



Equipment connections for clock recovery trigger test



A 1.25 GB/s pattern using clock recovery trigger

Pattern sync trigger

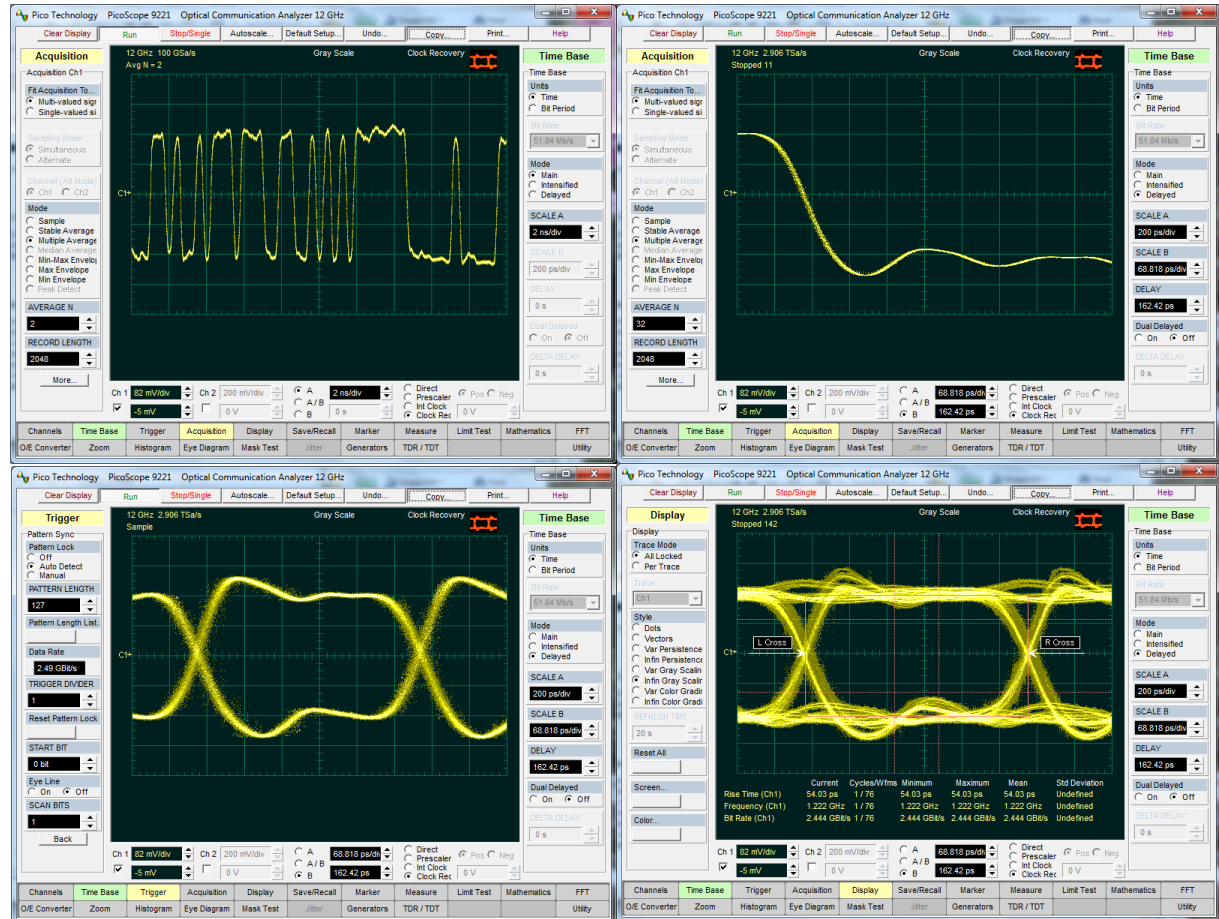
Use pattern sync menu to provide pattern lock trigger, and generate an eye line.

Pattern Lock Trigger:

...is the ability of the PicoScope 9000A to internally generate and lock onto a pattern trigger.

Eye line:

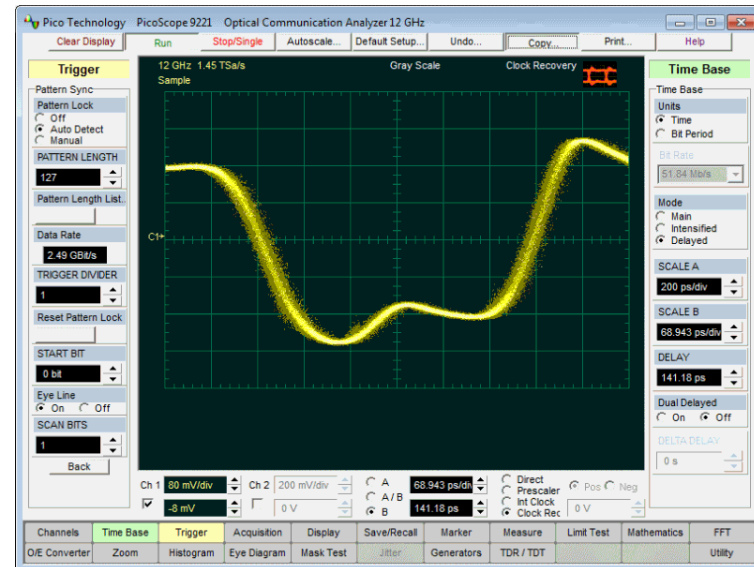
...is used to average eye diagrams and to view specific bit trajectories. The **Eye Line** mode uses the pattern lock feature to establish a pattern sync trigger and then to use that trigger to walk through each bit of the data pattern



Building an eye diagram

The eye diagram is valuable for giving a comprehensive view of all signal integrity faults (except clock jitter):

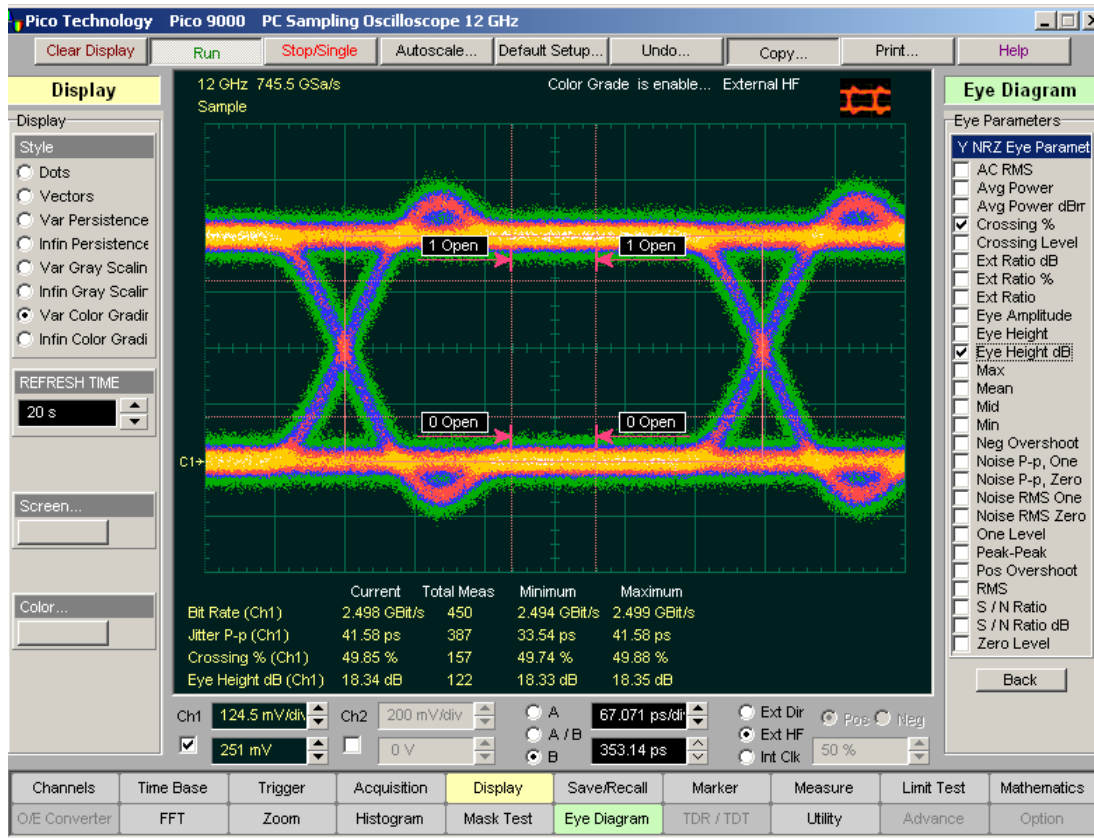
- ▶ Noise
- ▶ Jitter
- ▶ Reflections
- ▶ Ringing
- ▶ Inter-symbol interference
- ▶ Power and ground coupling



The process of building an eye diagram includes serial acquisitions of the waveform database

NRZ Eye Diagram Measurements

The PicoScope 9000 quickly measures 42 fundamental parameters used to characterise non-return-to-zero (NRZ) signals. Up to four parameters can be measured simultaneously.



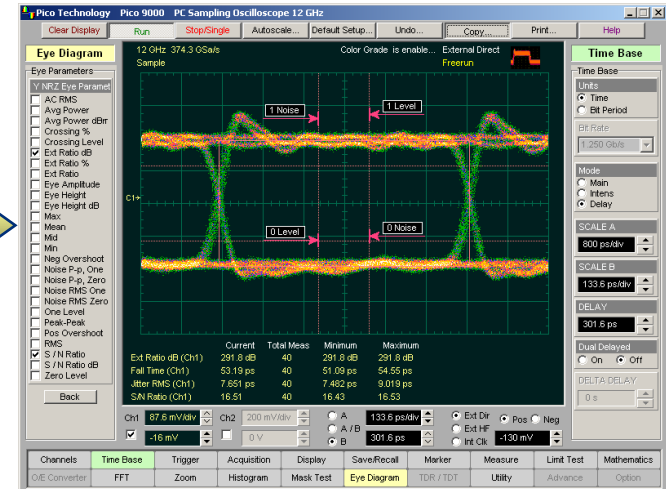
The PicoScope 9000 displaying 4 automatic measurements on a 2.5-Gbit NRZ eye diagram

Examples of NRZ Measurements

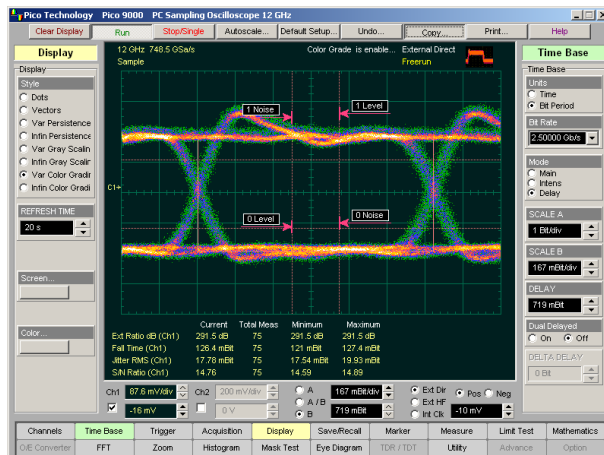


Measurement of 622-Mbit eye diagram

Measurement of 1.25-Gbit eye diagram

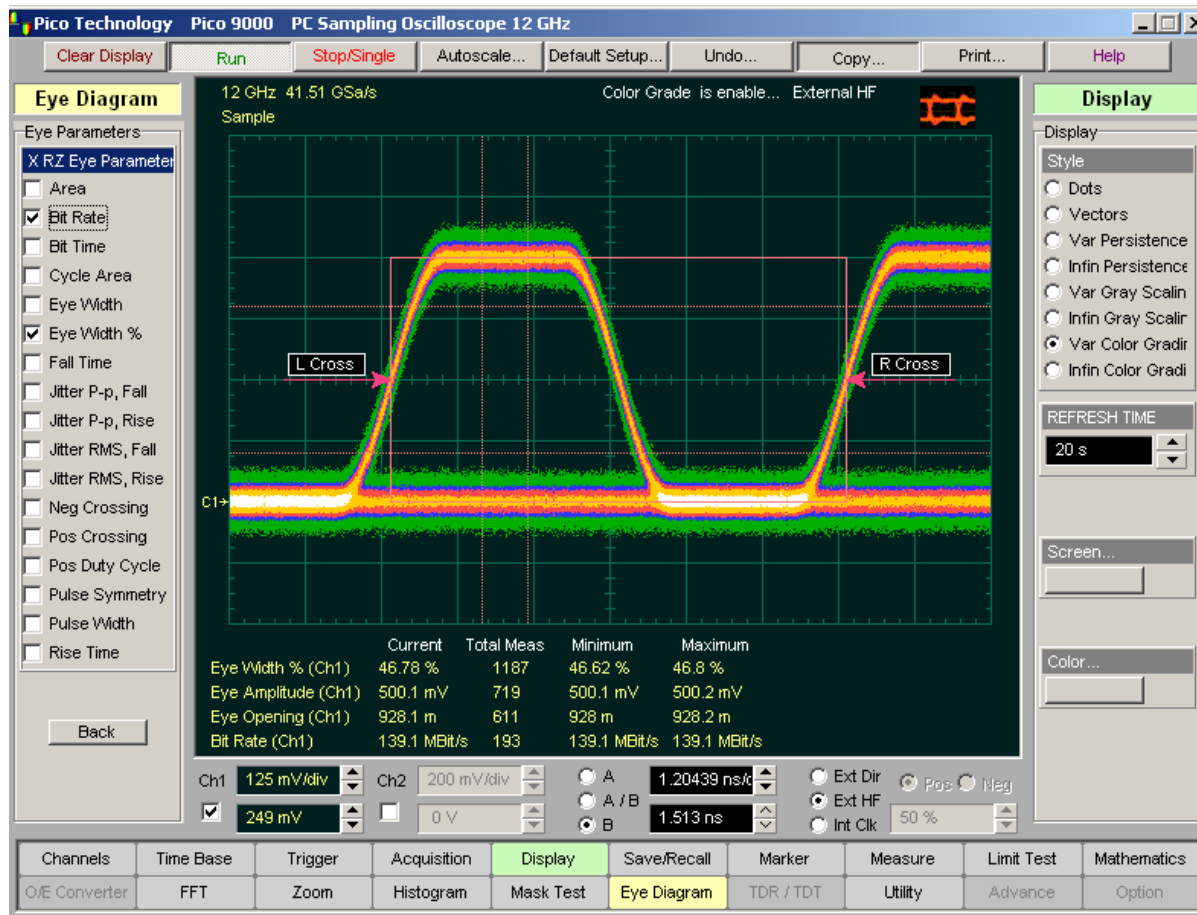


Measurement of 2.5-Gbit eye diagram



RZ Eye Diagram Analysis

The PicoScope 9000 quickly measures 43 fundamental parameters used to characterise return-to-zero (RZ) signals. Up to four parameters can be measured simultaneously.



The PicoScope 9000 measuring a 139-Mbit RZ eye diagram

Mask Test

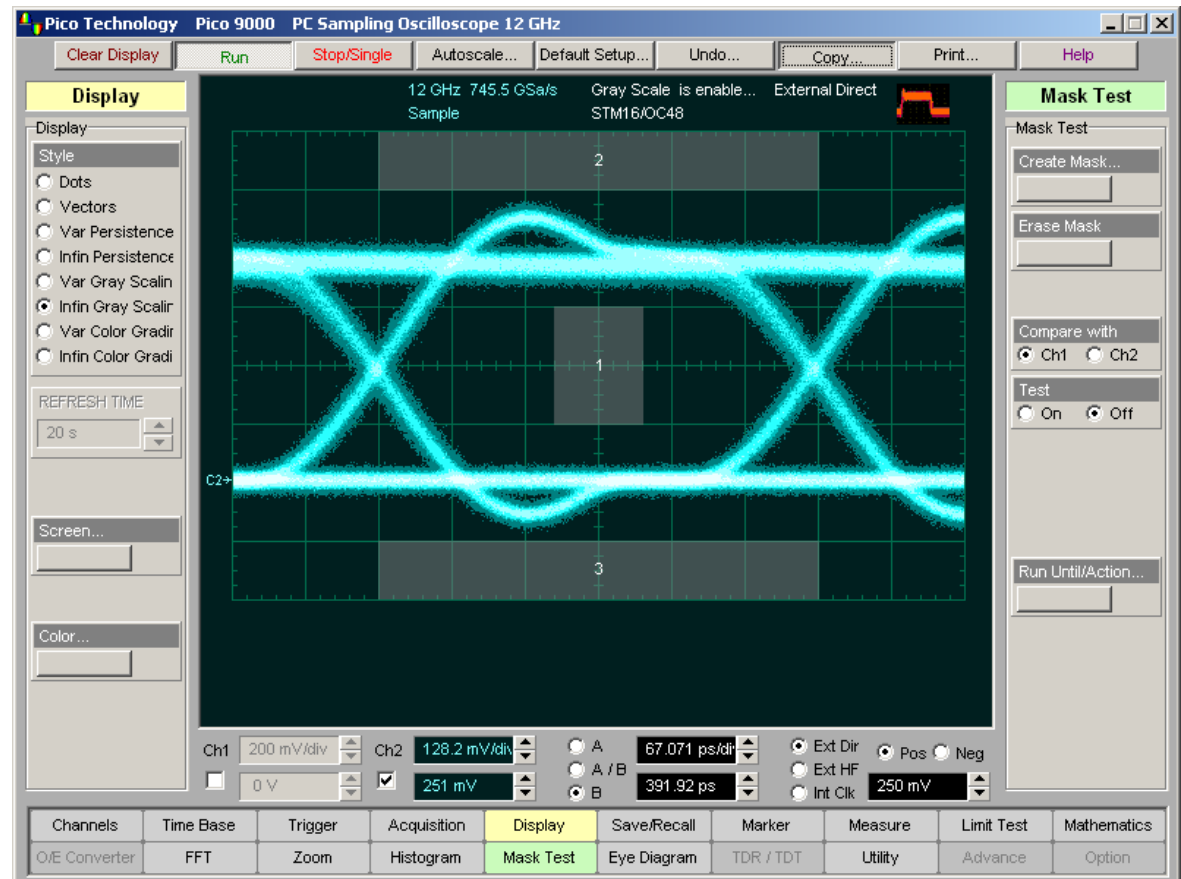
For eye-diagram masks, such as those specified by the SONET and SDH standards, the PicoScope 9000 supports on-board mask drawing for visual comparison. The display can create grey-scaled or colour-graded displays to aid in analysing noise and jitter in eye-diagrams.

Mask test quickly characterises:

- ▶ Noise
- ▶ Jitter
- ▶ Aberrations
- ▶ Rise time
- ▶ Fall time

The on-board mask drawing capability allows simple, operator-independent visual comparison of signal with standard mask.

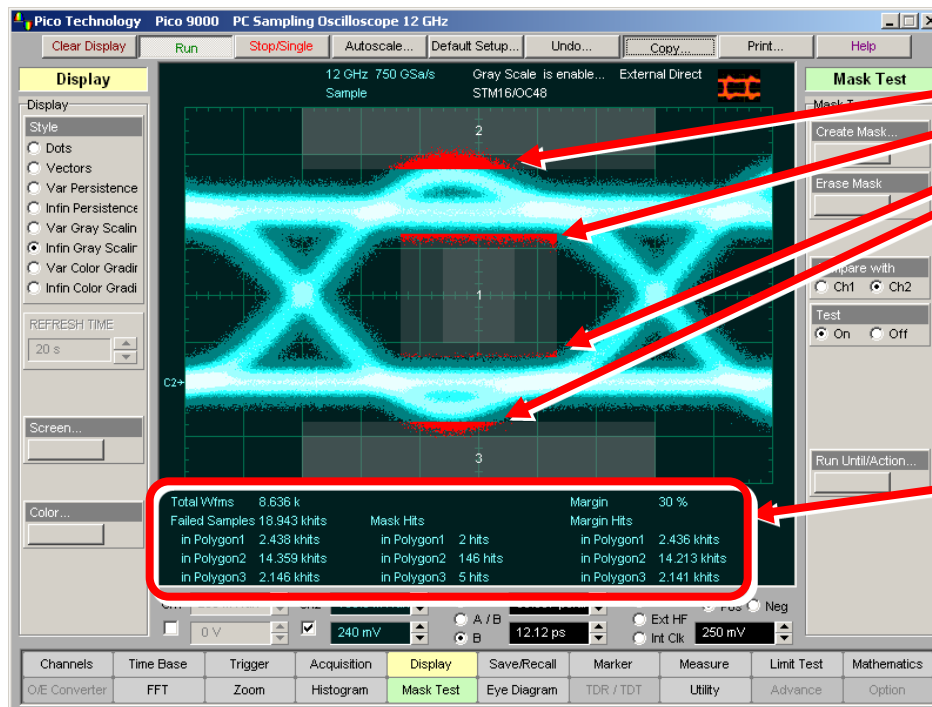
SONET/SDH (OC64/STM16)
signal compared with the
standard mask, showing a
compliant waveform



Mask Margins

Mask margins are used to determine the margin of compliance for a standard or scaled mask.

The PicoScope 9000 goes beyond basic testing with mask margin analysis for process monitoring.



Mask hits/failures are easily viewed with red pixels

Mask test results show:

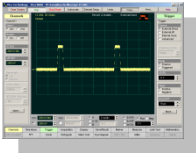
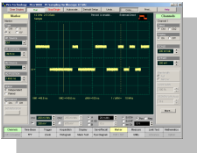
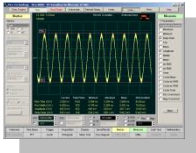
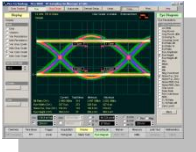
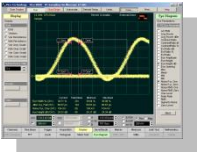
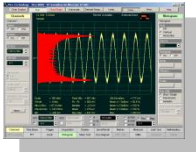
- ▶ Total waveforms
- ▶ Failed samples
- ▶ Mask hits
- ▶ Mask margin value
- ▶ Margin hits
- ▶ Margin hits in polygon

Mask margins are used to determine the margin of compliance for a standard 2.5 Gbps STM16/OC48 eye diagram or scaled mask

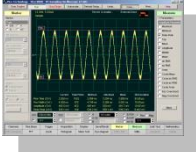


Measurements and Tests

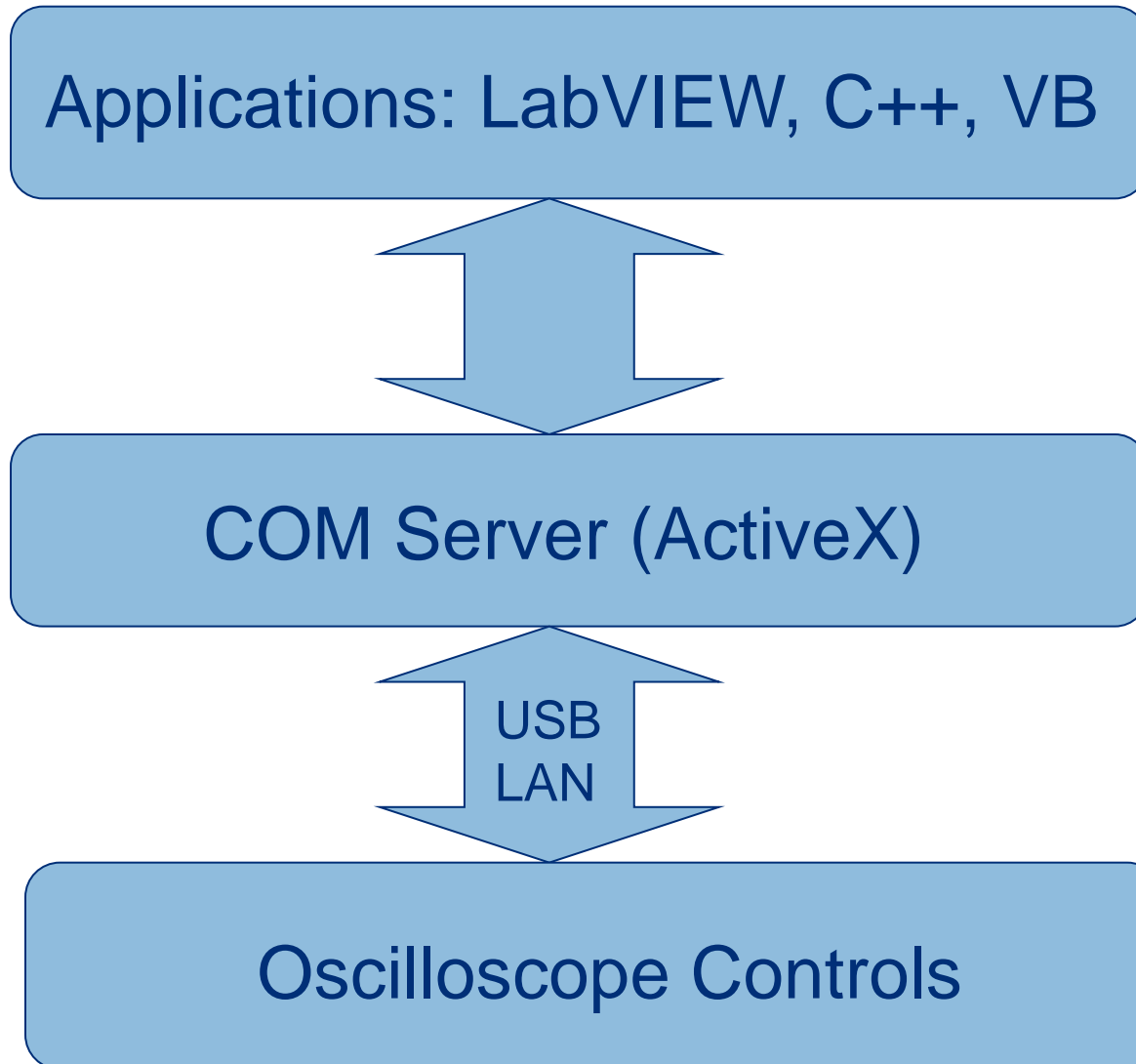


Types of Measurements

<h3>Graticule Measurements</h3>  <p>10 by 8 display graticule with Grid, Axes, Frame and Off options</p>	<h3>Marker Measurements</h3>  <p>Two X, Y, or XY markers provide absolute, delta or ratiometric measurements</p>	<h3>Pulse Measurements</h3>  <p>19 Amplitude, 29 Timing and 5 FFT measurements can be performed automatically</p>
<h3>NRZ Eye Measurements</h3>  <p>Measurement list includes 42 NRZ eye parameters</p>	<h3>RZ Eye Measurements</h3>  <p>43 automatic measurements are built for characterisation of RZ signals</p>	<h3>Histogram Measurements</h3>  <p>Up to 15 statistical measurements of vertical and horizontal histograms</p>

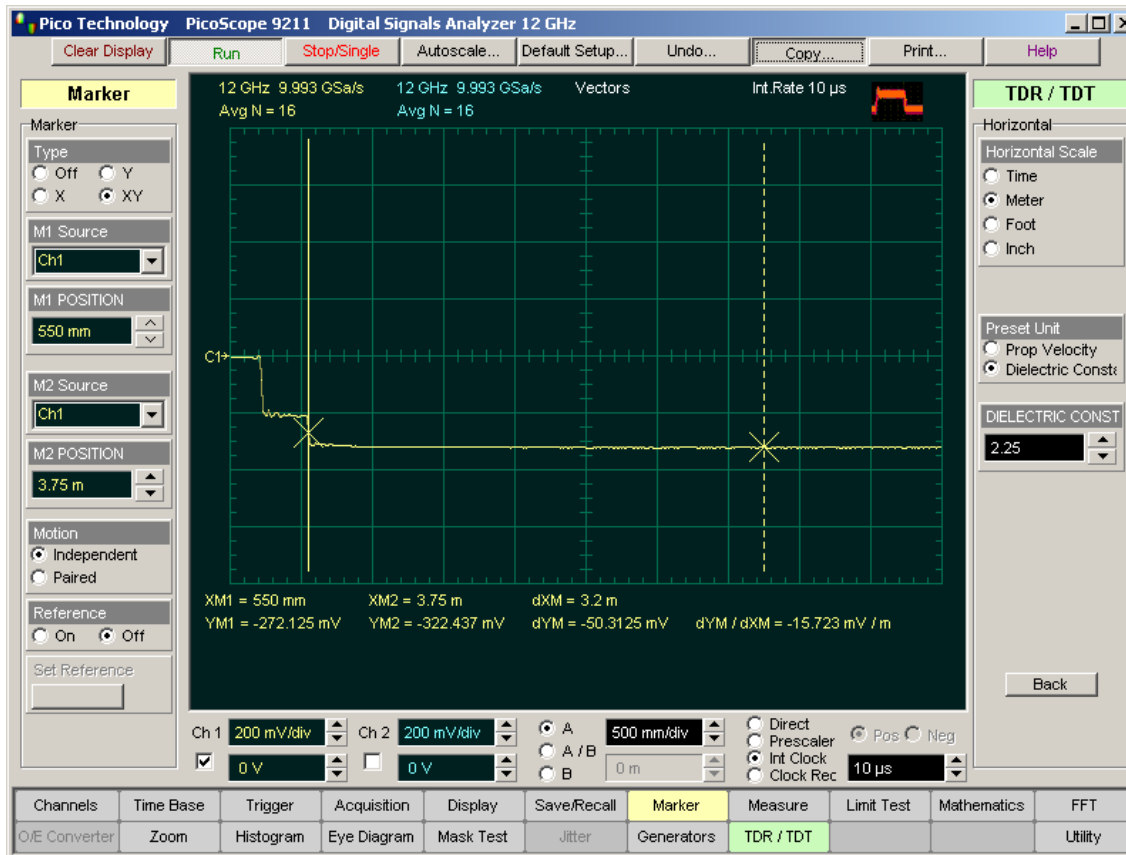
Types of Measurement Test

<h3>Limit Test</h3>  <p>Allows you to automatically compare up to 4 measurement results with pass or fail limits</p>	<h3>Mask Test</h3>  <p>Standard, auto or custom masks can be used for mask test</p>	<h3>Mask Margin Test</h3>  <p>Test is used to determine the margin of compliance for a standard or scaled mask</p>
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TDR/TDT Measurements

Time Domain Reflectometry (TDR) is a method of characterizing a transmission line or network by sending a signal into one end and monitoring the electrical reflections.



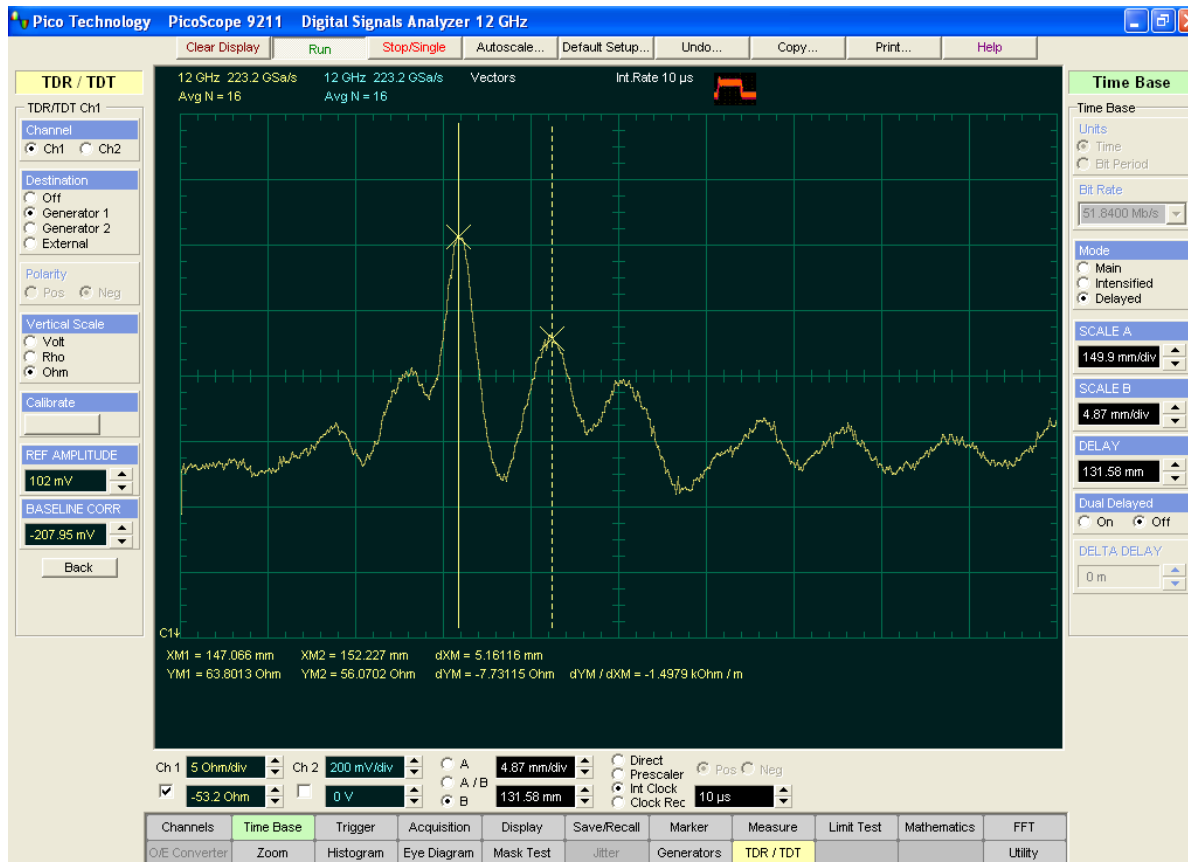
A TDR step can also be used to make Time Domain Transmission (TDT) measurements. TDT is a technique that allows you to measure the response of a system by sending steps through a device and monitoring the output of the device.

The measurements are made on signals transmitted through the device, rather than reflections from the device (as in TDR).

An example of Z-profile of transmission line. Both markers provide distance and Ohm measurements

TDR/TDT applications

TDR response from analyzing a PCB, showing three vias 5mm apart



PicoScope 9000 Specifications



VERTICAL

- ▶ DC to 12 GHz bandwidth
- ▶ 29.2 ps rise time
- ▶ Two channels
- ▶ $\pm 2\%$ vertical gain accuracy
- ▶ 16-bit vertical resolution
- ▶ < 2.0 mV RMS noise
- ▶ ± 1 V input range

HORIZONTAL

- ▶ Dual timebase 10 ps/div to 50 ms/div
- ▶ $\pm 0.2\% \pm 15$ ps time interval accuracy
- ▶ < 200 fs sampling interval
- ▶ Up to 4 k-point/channel buffer size

TRIGGER

- ▶ DC to 1 GHz full direct trigger
- ▶ 10 GHz prescaled trigger
- ▶ < 3.5 ps RMS jitter
- ▶ 2.7 GHz Clock recovery
- ▶ Pattern sync trigger

OPERATIONAL

- ▶ Power consumption: 15 W max
- ▶ Weight: 1 kg
- ▶ Size: W170 x H40 x D255 mm

TDR/TDT

- ▶ Two channels
- ▶ Vertical scales: Volts, Rho (2mrho/div to 2 rho/div), Ohm (1 ohm/div to 100 ohm/div)
- ▶ Horizontal scale: Time or distance (Meter, Foot, inch)
- ▶ TDR stimulus from internal or external generators

Signal Generators (9211A)

- ▶ Modes: Step, Coarse timebase, Pulse, NRZ and RZ
- ▶ 100 ps risetime (typ) for Step (TDR)

MEASUREMENTS and ANALYSIS

- ▶ High-resolution cursors, automatic waveform measurements, statistics and pass / fail limit tests
- ▶ Waveform processing including FFT with five FFT windows

UTILITY

- ▶ Autoscale
- ▶ Automatic calibration
- ▶ Windows XP, Vista and Windows 7
- ▶ Built-in information system using Windows Help

Question and answers